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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Obsolete
Core Processor	HCS12
Core Size	16-Bit
Speed	25MHz
Connectivity	I ² C, SCI, SPI
Peripherals	PWM, WDT
Number of I/O	91
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	4K x 8
RAM Size	12K x 8
Voltage - Supply (Vcc/Vdd)	2.35V ~ 5.25V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	112-LQFP
Supplier Device Package	112-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc9s12a256bcpv

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- Two 8-channel Analog-to-Digital Converters
 - 10-bit resolution
 - External conversion trigger capability
- Five 1M bit per second, CAN 2.0 A, B software compatible modules
 - Five receive and three transmit buffers
 - Flexible identifier filter programmable as 2 x 32 bit, 4 x 16 bit or 8 x 8 bit
 - Four separate interrupt channels for Rx, Tx, error and wake-up
 - Low-pass filter wake-up function
 - Loop-back for self test operation
- Enhanced Capture Timer
 - 16-bit main counter with 7-bit prescaler
 - 8 programmable input capture or output compare channels
 - Two 8-bit or one 16-bit pulse accumulators
- 8 PWM channels
 - Programmable period and duty cycle
 - 8-bit 8-channel or 16-bit 4-channel
 - Separate control for each pulse width and duty cycle
 - Center-aligned or left-aligned outputs
 - Programmable clock select logic with a wide range of frequencies
 - Fast emergency shutdown input
 - Usable as interrupt inputs
- Serial interfaces
 - Two asynchronous Serial Communications Interfaces (SCI)
 - Three Synchronous Serial Peripheral Interface (SPI)
- Byte Data Link Controller (BDLC)
 - SAE J1850 Class B Data Communications Network Interface Compatible and ISO Compatible for Low-Speed (<125 Kbps) Serial Data Communications in Automotive Applications
- Inter-IC Bus (IIC)
 - Compatible with I2C Bus standard
 - Multi-master operation
 - Software programmable for one of 256 different serial clock frequencies
- 112-Pin LQFP package
 - I/O lines with 5V input and drive capability

\$0010 - \$0014**MMC map 1 of 4 (Core User Guide)**

Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
\$0012	INITEE	Read: EE15	Write: EE14	EE13	EE12	0	0	0	EEON
\$0013		Read: 0	Write: 0	0	0	EXSTR1	EXSTRO	ROMHM	ROMON
\$0014	MTST0	Read: Bit 7	Write: 6	5	4	3	2	1	Bit 0

\$0015 - \$0016**INT map 1 of 2 (Core User Guide)**

Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
\$0015	ITCR	Read: 0	Write: 0	0	WRINT	ADR3	ADR2	ADR1	ADR0
\$0016		Read: INTE	Write: INTC	INTA		INT8	INT6	INT4	INT2
	ITEST								INT0

\$0017 - \$0017**MMC map 2 of 4 (Core User Guide)**

Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
\$0017	MTST1	Read: Bit 7	Write: 6	5	4	3	2	1	Bit 0

\$0018 - \$001B**Miscellaneous Peripherals (Device User Guide, Table 1-3)**

Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
\$0018	Reserved	Read: 0	Write: 0	0	0	0	0	0	0
\$0019		Read: 0	Write: 0	0	0	0	0	0	0
\$001A	PARTIDH	Read: ID15	Write: ID14	ID13	ID12	ID11	ID10	ID9	ID8
\$001B		Read: ID7	Write: ID6	ID5	ID4	ID3	ID2	ID1	ID0

\$001C - \$001D**MMC map 3 of 4 (Core and Device User Guide, Table 1-4)**

Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
\$001C	MEMSIZ0	Read: reg_sw0	Write: 0	eep_sw1	eep_sw0	0	ram_sw2	ram_sw1	ram_sw0
\$001D		Read: rom_sw1	Write: rom_sw0	0	0	0	0	pag_sw1	pag_sw0
	MEMSIZ1								

\$0034 - \$003F

CRG (Clock and Reset Generator)

Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
\$003D	FORBYP TEST ONLY	Read:	RTIBYP	COPBYP	0	PLLBYP	0	0	FCM
		Write:							0
\$003E	CTCTL TEST ONLY	Read:	TCTL7	TCTL6	TCTL5	TCTL4	TCLT3	TCTL2	TCTL1
		Write:							TCTL0
\$003F	ARMCOP	Read:	0	0	0	0	0	0	0
		Write:	Bit 7	6	5	4	3	2	1
									Bit 0

\$0040 - \$007F

ECT (Enhanced Capture Timer 16 Bit 8 Channels)

Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
\$0040	TIOS	Read:	IOS7	IOS6	IOS5	IOS4	IOS3	IOS2	IOS1
		Write:							IOS0
\$0041	CFORC	Read:	0	0	0	0	0	0	0
		Write:	FOC7	FOC6	FOC5	FOC4	FOC3	FOC2	FOC1
\$0042	OC7M	Read:	OC7M7	OC7M6	OC7M5	OC7M4	OC7M3	OC7M2	OC7M1
		Write:							OC7M0
\$0043	OC7D	Read:	OC7D7	OC7D6	OC7D5	OC7D4	OC7D3	OC7D2	OC7D1
		Write:							OC7D0
\$0044	TCNT (hi)	Read:	Bit 15	14	13	12	11	10	9
		Write:							Bit 8
\$0045	TCNT (lo)	Read:	Bit 7	6	5	4	3	2	1
		Write:							Bit 0
\$0046	TSCR1	Read:	TEN	TSWAI	TSFRZ	TFFCA	0	0	0
		Write:							0
\$0047	TTOV	Read:	TOV7	TOV6	TOV5	TOV4	TOV3	TOV2	TOV1
		Write:							TOV0
\$0048	TCTL1	Read:	OM7	OL7	OM6	OL6	OM5	OL5	OM4
		Write:							OL4
\$0049	TCTL2	Read:	OM3	OL3	OM2	OL2	OM1	OL1	OM0
		Write:							OL0
\$004A	TCTL3	Read:	EDG7B	EDG7A	EDG6B	EDG6A	EDG5B	EDG5A	EDG4B
		Write:							EDG4A
\$004B	TCTL4	Read:	EDG3B	EDG3A	EDG2B	EDG2A	EDG1B	EDG1A	EDG0B
		Write:							EDG0A
\$004C	TIE	Read:	C7I	C6I	C5I	C4I	C3I	C2I	C1I
		Write:							C0I
\$004D	TSCR2	Read:	TOI	0	0	0	TCRE	PR2	PR1
		Write:							PR0
\$004E	TFLG1	Read:	C7F	C6F	C5F	C4F	C3F	C2F	C1F
		Write:							C0F
\$004F	TFLG2	Read:	TOF	0	0	0	0	0	0
		Write:							0
\$0050	TC0 (hi)	Read:	Bit 15	14	13	12	11	10	9
		Write:							Bit 8
\$0051	TC0 (lo)	Read:	Bit 7	6	5	4	3	2	1
		Write:							Bit 0
\$0052	TC1 (hi)	Read:	Bit 15	14	13	12	11	10	9
		Write:							Bit 8

Flash Control Register (fts512k4)

Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0	
\$0104	FPROT	Read: Write:	FPOOPEN	NV6	FPHDIS	FPHS1	FPHS0	FPLDIS	FPLS1	FPLS0
\$0105		Read: Write:	CBEIF	CCIF	PVIOL	ACCERR	0	BLANK	0	0
\$0106	FCMD	Read: Write:	0	CMDB6	CMDB5	0	0	CMDB2	0	CMDB0
\$0107		Read: Write:	0	0	0	0	0	0	0	0
\$0108	FADDRHI	Read: Write:	0	Bit 14	13	12	11	10	9	Bit 8
\$0109		Read: Write:	Bit 7	6	5	4	3	2	1	Bit 0
\$010A	FDATAHI	Read: Write:	Bit 15	14	13	12	11	10	9	Bit 8
\$010B		Read: Write:	Bit 7	6	5	4	3	2	1	Bit 0
\$010C	Reserved	Read: Write:	0	0	0	0	0	0	0	0
\$010D		Read: Write:	0	0	0	0	0	0	0	0
\$010E	Reserved	Read: Write:	0	0	0	0	0	0	0	0
\$010F		Read: Write:	0	0	0	0	0	0	0	0

\$0110 - \$011B**EEPROM Control Register (eets4k)**

Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0	
\$0110	ECLKDIV	Read: Write:	EDIVLD	PRDIV8	EDIV5	EDIV4	EDIV3	EDIV2	EDIV1	EDIV0
\$0111		Read: Write:	0	0	0	0	0	0	0	0
\$0112	Reserved for Factory Test	Read: Write:	0	0	0	0	0	0	0	0
\$0113		Read: Write:	CBEIE	CCIE	0	0	0	0	0	0
\$0114	EPROT	Read: Write:	EPOOPEN	NV6	NV5	NV4	EPDIS	EP2	EP1	EP0
\$0115		Read: Write:	CBEIF	CCIF	PVIOL	ACCERR	0	BLANK	0	0
\$0116	ECMD	Read: Write:	0	CMDB6	CMDB5	0	0	CMDB2	0	CMDB0
\$0117		Read: Write:	0	0	0	0	0	0	0	0
\$0118	EADDRHI	Read: Write:	0	0	0	0	0	10	9	Bit 8

Table 1-2 Detailed MSCAN Foreground Receive and Transmit Buffer Layout

Address	Name		Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
\$xxx2	Extended ID	Read:	ID14	ID13	ID12	ID11	ID10	ID9	ID8	ID7
	Standard ID	Read:								
	CANxRIDR2	Write:								
\$xxx3	Extended ID	Read:	ID6	ID5	ID4	ID3	ID2	ID1	ID0	RTR
	Standard ID	Read:								
	CANxRIDR3	Write:								
\$xxx4-\$xxxB	CANxRDSR0 - CANxRDSR7	Read:	DB7	DB6	DB5	DB4	DB3	DB2	DB1	DB0
		Write:								
\$xxxC	CANRxDLR	Read:					DLC3	DLC2	DLC1	DLC0
		Write:								
\$xxxD	Reserved	Read:								
		Write:								
\$xxxE	CANxRTSRH	Read:	TSR15	TSR14	TSR13	TSR12	TSR11	TSR10	TSR9	TSR8
		Write:								
\$xxxF	CANxRTSRL	Read:	TSR7	TSR6	TSR5	TSR4	TSR3	TSR2	TSR1	TSR0
		Write:								
\$xx10	Extended ID CANxTIDR0	Read:	ID28	ID27	ID26	ID25	ID24	ID23	ID22	ID21
	Standard ID	Read:	ID10	ID9	ID8	ID7	ID6	ID5	ID4	ID3
		Write:								
\$xx10	Extended ID CANxTIDR1	Read:	ID20	ID19	ID18	SRR=1	IDE=1	ID17	ID16	ID15
	Standard ID	Read:	ID2	ID1	ID0	RTR	IDE=0			
		Write:								
\$xx12	Extended ID CANxTIDR2	Read:	ID14	ID13	ID12	ID11	ID10	ID9	ID8	ID7
	Standard ID	Read:								
		Write:								
\$xx13	Extended ID CANxTIDR3	Read:	ID6	ID5	ID4	ID3	ID2	ID1	ID0	RTR
	Standard ID	Read:								
		Write:								
\$xx14-\$xx1B	CANxTDSR0 - CANxTDSR7	Read:	DB7	DB6	DB5	DB4	DB3	DB2	DB1	DB0
		Write:								
\$xx1C	CANxTDLR	Read:					DLC3	DLC2	DLC1	DLC0
		Write:								
\$xx1D	CONxTTBPR	Read:	PRI07	PRI06	PRI05	PRI04	PRI03	PRI02	PRI01	PRI00
		Write:								
\$xx1E	CANxTTSRH	Read:	TSR15	TSR14	TSR13	TSR12	TSR11	TSR10	TSR9	TSR8
		Write:								
\$xx1F	CANxTTSRL	Read:	TSR7	TSR6	TSR5	TSR4	TSR3	TSR2	TSR1	TSR0
		Write:								

\$0200 - \$023F

CAN3 (Motorola Scalable CAN - MSCAN)

Address	Name		Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
\$0219	CAN3IDAR5	Read: Write:	AC7	AC6	AC5	AC4	AC3	AC2	AC1	AC0
\$021A	CAN3IDAR6	Read: Write:	AC7	AC6	AC5	AC4	AC3	AC2	AC1	AC0
\$021B	CAN3IDAR7	Read: Write:	AC7	AC6	AC5	AC4	AC3	AC2	AC1	AC0
\$021C	CAN3IDMR4	Read: Write:	AM7	AM6	AM5	AM4	AM3	AM2	AM1	AM0
\$021D	CAN3IDMR5	Read: Write:	AM7	AM6	AM5	AM4	AM3	AM2	AM1	AM0
\$021E	CAN3IDMR6	Read: Write:	AM7	AM6	AM5	AM4	AM3	AM2	AM1	AM0
\$021F	CAN3IDMR7	Read: Write:	AM7	AM6	AM5	AM4	AM3	AM2	AM1	AM0
\$0220 - \$022F	CAN3RXFG	Read: Write:	FOREGROUND RECEIVE BUFFER see Table 1-2							
\$0230 - \$023F	CAN3TXFG	Read: Write:	FOREGROUND TRANSMIT BUFFER see Table 1-2							

\$0240 - \$027F

PIM (Port Integration Module PIM_9DP256)

Address	Name		Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
\$0240	PTT	Read: Write:	PTT7	PTT6	PTT5	PTT4	PTT3	PTT2	PTT1	PTT0
\$0241	PTIT	Read: Write:	PTIT7	PTIT6	PTIT5	PTIT4	PTIT3	PTIT2	PTIT1	PTIT0
\$0242	DDRT	Read: Write:	DDRT7	DDRT6	DDRT5	DDRT4	DDRT3	DDRT2	DDRT1	DDRT0
\$0243	RDRT	Read: Write:	RDRT7	RDRT6	RDRT5	RDRT4	RDRT3	RDRT2	RDRT1	RDRT0
\$0244	PERT	Read: Write:	PERT7	PERT6	PERT5	PERT4	PERT3	PERT2	PERT1	PERT0
\$0245	PPST	Read: Write:	PPST7	PPST6	PPST5	PPST4	PPST3	PPST2	PPST1	PPST0
\$0246	Reserved	Read: Write:	0	0	0	0	0	0	0	0
\$0247	Reserved	Read: Write:	0	0	0	0	0	0	0	0
\$0248	PTS	Read: Write:	PTS7	PTS6	PTS5	PTS4	PTS3	PTS2	PTS1	PTS0
\$0249	PTIS	Read: Write:	PTIS7	PTIS6	PTIS5	PTIS4	PTIS3	PTIS2	PTIS1	PTIS0
\$024A	DDRS	Read: Write:	DDRS7	DDRS6	DDRS5	DDRS4	DDRS3	DDRS2	DDRS1	DDRS0
\$024B	RDRS	Read: Write:	RDRS7	RDRS6	RDRS5	RDRS4	RDRS3	RDRS2	RDRS1	RDRS0
\$024C	PERS	Read: Write:	PERS7	PERS6	PERS5	PERS4	PERS3	PERS2	PERS1	PERS0
\$024D	PPSS	Read: Write:	PPSS7	PPSS6	PPSS5	PPSS4	PPSS3	PPSS2	PPSS1	PPSS0

Section 2 Signal Description

This section describes signals that connect off-chip. It includes a pinout diagram, a table of signal properties, and detailed discussion of signals. It is built from the signal description sections of the Block User Guides of the individual IP blocks on the device.

2.1 Device Pinout

The MC9S12DP256B/MC9S12DT256/MC9S12DJ256 and MC9S12DG256 is available in a 112-pin low profile quad flat pack (LQFP) and MC9S12DJ256 is also available in a 80-pin quad flat pack (QFP). Most pins perform two or more functions, as described in the Signal Descriptions. **Figure 2-1** and **Figure 2-3** show the pin assignments.

Section 5 Resets and Interrupts

5.1 Overview

Consult the Exception Processing section of the HCS12 Core User Guide for information on resets and interrupts.

5.2 Vectors

5.2.1 Vector Table

Table 5-1 lists interrupt sources and vectors in default order of priority.

Table 5-1 Interrupt Vector Locations

Vector Address	Interrupt Source	CCR Mask	Local Enable	HPrio Value to Elevate
\$FFFE, \$FFFF	Reset	None	None	—
\$FFFC, \$FFFD	Clock Monitor fail reset	None	PLLCTL (CME, SCME)	—
\$FFFA, \$FFFB	COP failure reset	None	COP rate select	—
\$FFF8, \$FFF9	Unimplemented instruction trap	None	None	—
\$FFF6, \$FFF7	SWI	None	None	—
\$FFF4, \$FFF5	XIRQ	X-Bit	None	—
\$FFF2, \$FFF3	IRQ	I-Bit	IRQCR (IRQEN)	\$F2
\$FFF0, \$FFF1	Real Time Interrupt	I-Bit	CRGINT (RTIE)	\$F0
\$FFEE, \$FFEF	Enhanced Capture Timer channel 0	I-Bit	TIE (COI)	\$EE
\$FFEC, \$FFED	Enhanced Capture Timer channel 1	I-Bit	TIE (C1I)	\$EC
\$FFEA, \$FFEB	Enhanced Capture Timer channel 2	I-Bit	TIE (C2I)	\$EA
\$FFE8, \$FFE9	Enhanced Capture Timer channel 3	I-Bit	TIE (C3I)	\$E8
\$FFE6, \$FFE7	Enhanced Capture Timer channel 4	I-Bit	TIE (C4I)	\$E6
\$FFE4, \$FFE5	Enhanced Capture Timer channel 5	I-Bit	TIE (C5I)	\$E4
\$FFE2, \$FFE3	Enhanced Capture Timer channel 6	I-Bit	TIE (C6I)	\$E2
\$FFE0, \$FFE1	Enhanced Capture Timer channel 7	I-Bit	TIE (C7I)	\$E0
\$FFDE, \$FFDF	Enhanced Capture Timer overflow	I-Bit	TSRC2 (TOF)	\$DE
\$FFDC, \$FFDD	Pulse accumulator A overflow	I-Bit	PACTL (PAOVI)	\$DC
\$FFDA, \$FFDB	Pulse accumulator input edge	I-Bit	PACTL (PAI)	\$DA
\$FFD8, \$FFD9	SPI0	I-Bit	SP0CR1 (SPIE, SPTIE)	\$D8
\$FFD6, \$FFD7	SCI0	I-Bit	SC0CR2 (TIE, TCIE, RIE, ILIE)	\$D6
\$FFD4, \$FFD5	SCI1	I-Bit	SC1CR2 (TIE, TCIE, RIE, ILIE)	\$D4
\$FFD2, \$FFD3	ATD0	I-Bit	ATD0CTL2 (ASCIE)	\$D2
\$FFD0, \$FFD1	ATD1	I-Bit	ATD1CTL2 (ASCIE)	\$D0
\$FFCE, \$FFCF	Port J	I-Bit	PTJIF (PTJIE)	\$CE
\$FFCC, \$FFCD	Port H	I-Bit	PTHIF(PTHIE)	\$CC
\$FFCA, \$FFCB	Modulus Down Counter underflow	I-Bit	MCCTL(MCZI)	\$CA

\$FFC8, \$FFC9	Pulse Accumulator B Overflow	I-Bit	PBCTL(PBOVI)	\$C8
\$FFC6, \$FFC7	CRG PLL lock	I-Bit	CRGINT(LOCKIE)	\$C6
\$FFC4, \$FFC5	CRG Self Clock Mode	I-Bit	CRGINT (SCMIE)	\$C4
\$FFC2, \$FFC3	BDLC	I-Bit	DLCBCR1(IE)	\$C2
\$FFC0, \$FFC1	IIC Bus	I-Bit	IBCR (IBIE)	\$C0
\$FFBE, \$FFBF	SPI1	I-Bit	SP1CR1 (SPIE, SPTIE)	\$BE
\$FFBC, \$FFBD	SPI2	I-Bit	SP2CR1 (SPIE, SPTIE)	\$BC
\$FFBA, \$FFBB	EEPROM	I-Bit	EECTL(CCIE, CBEIE)	\$BA
\$FFB8, \$FFB9	FLASH	I-Bit	FCTL(CCIE, CBEIE)	\$B8
\$FFB6, \$FFB7	CAN0 wake-up	I-Bit	CAN0RIER (WUPIE)	\$B6
\$FFB4, \$FFB5	CAN0 errors	I-Bit	CAN0RIER (CSCIE, OVRIE)	\$B4
\$FFB2, \$FFB3	CAN0 receive	I-Bit	CAN0RIER (RXFIE)	\$B2
\$FFB0, \$FFB1	CAN0 transmit	I-Bit	CAN0TIER (TXEIE2-TXEIE0)	\$B0
\$FFAE, \$FFAF	CAN1 wake-up	I-Bit	CAN1RIER (WUPIE)	\$AE
\$FFAC, \$FFAD	CAN1 errors	I-Bit	CAN1RIER (CSCIE, OVRIE)	\$AC
\$FFAA, \$FFAB	CAN1 receive	I-Bit	CAN1RIER (RXFIE)	\$AA
\$FFA8, \$FFA9	CAN1 transmit	I-Bit	CAN1TIER (TXEIE2-TXEIE0)	\$A8
\$FFA6, \$FFA7	CAN2 wake-up	I-Bit	CAN2RIER (WUPIE)	\$A6
\$FFA4, \$FFA5	CAN2 errors	I-Bit	CAN2RIER (CSCIE, OVRIE)	\$A4
\$FFA2, \$FFA3	CAN2 receive	I-Bit	CAN2RIER (RXFIE)	\$A2
\$FFA0, \$FFA1	CAN2 transmit	I-Bit	CAN2TIER (TXEIE2-TXEIE0)	\$A0
\$FF9E, \$FF9F	CAN3 wake-up	I-Bit	CAN3RIER (WUPIE)	\$9E
\$FF9C, \$FF9D	CAN3 errors	I-Bit	CAN3RIER (TXEIE2-TXEIE0)	\$9C
\$FF9A, \$FF9B	CAN3 receive	I-Bit	CAN3RIER (RXFIE)	\$9A
\$FF98, \$FF99	CAN3 transmit	I-Bit	CAN3TIER (TXEIE2-TXEIE0)	\$98
\$FF96, \$FF97	CAN4 wake-up	I-Bit	CAN4RIER (WUPIE)	\$96
\$FF94, \$FF95	CAN4 errors	I-Bit	CAN4RIER (CSCIE, OVRIE)	\$94
\$FF92, \$FF93	CAN4 receive	I-Bit	CAN4RIER (RXFIE)	\$92
\$FF90, \$FF91	CAN4 transmit	I-Bit	CAN4TIER (TXEIE2-TXEIE0)	\$90
\$FF8E, \$FF8F	Port P Interrupt	I-Bit	PTPIF (PTPIE)	\$8E
\$FF8C, \$FF8D	PWM Emergency Shutdown	I-Bit	PWMSDN (PWMIE)	\$8C
\$FF80 to \$FF8B	Reserved			

5.3 Effects of Reset

When a reset occurs, MCU registers and control bits are changed to known start-up states. Refer to the respective module Block User Guides for register reset states.

5.3.1 I/O pins

Refer to the HCS12 Core User Guides for mode dependent pin configuration of port A, B, E and K out of reset.

Refer to the PIM Block User Guide for reset configurations of all peripheral module ports.

NOTE: For devices assembled in 80-pin QFP packages all non-bonded out pins should be configured as outputs after reset in order to avoid current drawn from floating inputs. Refer to **Table 2-1** for affected pins.

5.3.2 Memory

Refer to **Table 1-1** for locations of the memories depending on the operating mode after reset.

The RAM array is not automatically initialized out of reset.

Section 6 HCS12 Core Block Description

Consult the HCS12 Core User Guide for information about the HCS12 core modules, i.e. central processing unit (CPU), interrupt module (INT), module mapping control module (MMC), multiplexed external bus interface (MEBI), breakpoint module (BKP) and background debug mode module (BDM).

Table 6-1 Configuration of HCS12 Core

Name	Description	MC9S12DP256B Configuration
PUCR_RESET	PUCR reset state	\$90
NUM_INT	Interrupt Request Bus Width	56
INITEE_RST	INITEE reset state	\$01
INITEE_WOK	INITEE Write anytime in normal mode	INITEE register is writeable once in normal modes
PPAGE_SMOD_ONLY	PPAGE Write only in special mode	PPAGE register is writable in all modes,reset state of the PPAGE register is \$00

Section 7 Clock and Reset Generator (CRG) Block Description

Consult the CRG Block User Guide for information about the Clock and Reset Generator module.

7.1 Device-specific information

7.1.1 XCLKS

The XCLKS input signal is active low (see 2.3.13 PE7 / NOACC / XCLKS — Port E I/O Pin 7).

Section 8 Enhanced Capture Timer (ECT) Block Description

Consult the ECT_16B8C Block User Guide for information about the Enhanced Capture Timer module.

Section 9 Analog to Digital Converter (ATD) Block Description

There are two Analog to Digital Converters (ATD1 and ATD0) implemented on the MC9S12DP256B. Consult the ATD_10B8C Block User Guide for information about each Analog to Digital Converter module.

A.2 ATD Characteristics

This section describes the characteristics of the analog to digital converter.

A.2.1 ATD Operating Characteristics

The **Table A-8** shows conditions under which the ATD operates.

The following constraints exist to obtain full-scale, full range results:

$V_{SSA} \leq V_{RL} \leq V_{IN} \leq V_{RH} \leq V_{DDA}$. This constraint exists since the sample buffer amplifier can not drive beyond the power supply levels that it ties to. If the input level goes outside of this range it will effectively be clipped.

Table A-8 ATD Operating Characteristics

Conditions are shown in Table A-4 unless otherwise noted							
Num	C	Rating	Symbol	Min	Typ	Max	Unit
1	D	Reference Potential	V_{RL} V_{RH}	V_{SSA} $V_{DDA}/2$		$V_{DDA}/2$ V_{DDA}	V V
2	C	Differential Reference Voltage ¹	$V_{RH}-V_{RL}$	4.50	5.00	5.25	V
3	D	ATD Clock Frequency	f_{ATDCLK}	0.5		2.0	MHz
4	D	ATD 10-Bit Conversion Period	N_{CONV10} T_{CONV10}	14 7		28 14	Cycles μ s
5	D	ATD 8-Bit Conversion Period	N_{CONV8} T_{CONV8}	12 6		26 13	Cycles μ s
6	D	Recovery Time ($V_{DDA}=5.0$ Volts)	t_{REC}			20	μ s
7	P	Reference Supply current 2 ATD blocks on	I_{REF}			0.750	mA
8	P	Reference Supply current 1 ATD block on	I_{REF}			0.375	mA

NOTES:

1. Full accuracy is not guaranteed when differential voltage is less than 4.50V
2. The minimum time assumes a final sample period of 2 ATD clock cycles while the maximum time assumes a final sample period of 16 ATD clocks.

A.2.2 Factors influencing accuracy

Three factors - source resistance, source capacitance and current injection - have an influence on the accuracy of the ATD.

A.2.2.1 Source Resistance:

Due to the input pin leakage current as specified in **Table A-6** in conjunction with the source resistance there will be a voltage drop from the signal source to the ATD input. The maximum source resistance R_S

A.2.3 ATD accuracy

Table A-10 specifies the ATD conversion performance excluding any errors due to current injection, input capacitance and source resistance.

Table A-10 ATD Conversion Performance

Conditions are shown in Table A-4 unless otherwise noted $V_{REF} = V_{RH} - V_{RL} = 5.12V$. Resulting to one 8 bit count = 20mV and one 10 bit count = 5mV $f_{ATDCLK} = 2.0MHz$							
Num	C	Rating	Symbol	Min	Typ	Max	Unit
1	P	10-Bit Resolution	LSB		5		mV
2	P	10-Bit Differential Nonlinearity	DNL	-1		1	Counts
3	P	10-Bit Integral Nonlinearity	INL	-2.5	± 1.5	2.5	Counts
4	P	10-Bit Absolute Error ¹	AE	-3	± 2.0	3	Counts
5	P	8-Bit Resolution	LSB		20		mV
6	P	8-Bit Differential Nonlinearity	DNL	-0.5		0.5	Counts
7	P	8-Bit Integral Nonlinearity	INL	-1.0	± 0.5	1.0	Counts
8	P	8-Bit Absolute Error ¹	AE	-1.5	± 1.0	1.5	Counts

NOTES:

1. These values include the quantization error which is inherently 1/2 count for any A/D converter.

For the following definitions see also **Figure A-1**.

Differential Non-Linearity (DNL) is defined as the difference between two adjacent switching steps.

$$DNL(i) = \frac{V_i - V_{i-1}}{1LSB} - 1$$

The Integral Non-Linearity (INL) is defined as the sum of all DNLs:

$$INL(n) = \sum_{i=1}^n DNL(i) = \frac{V_n - V_0}{1LSB} - n$$

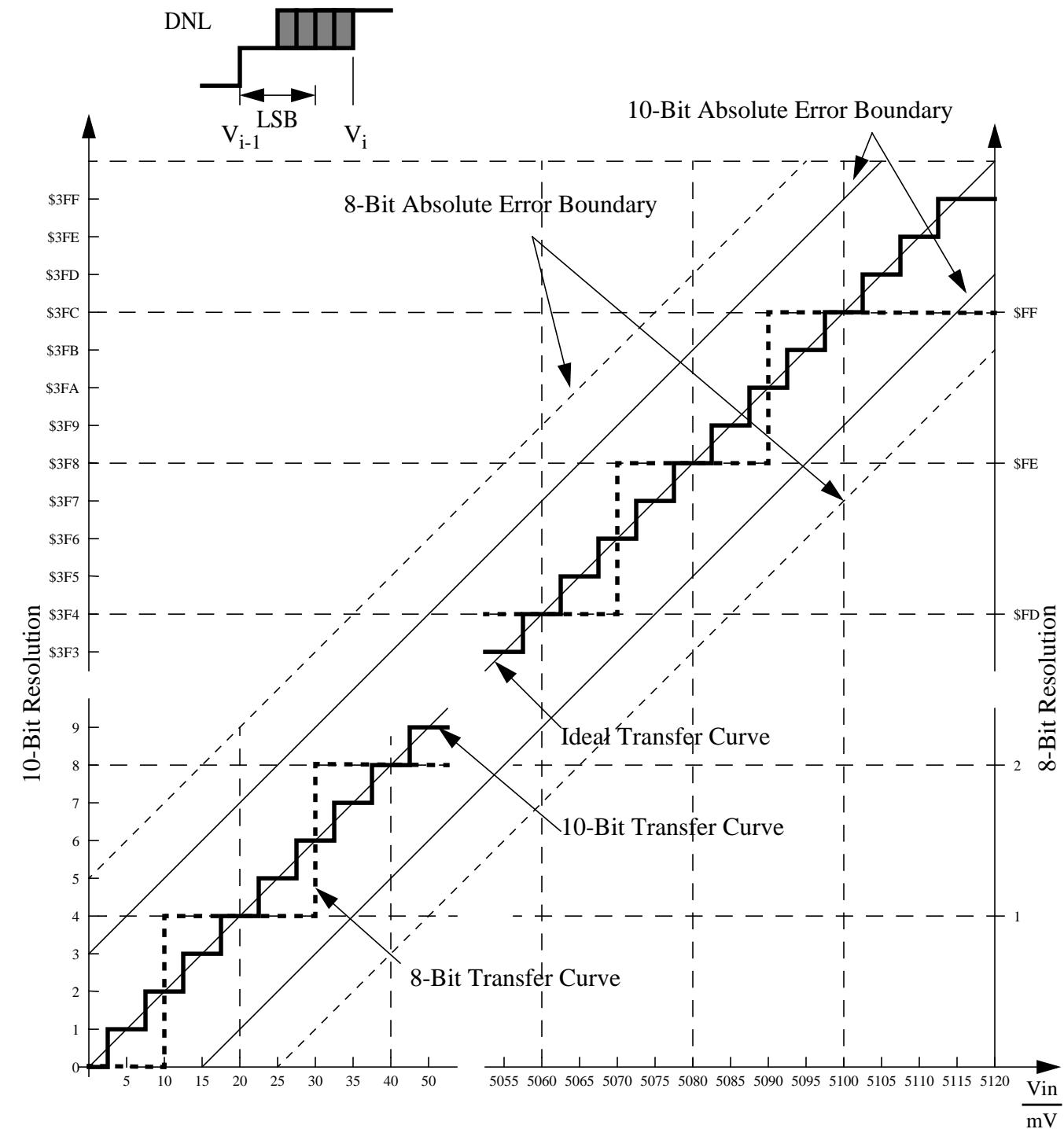


Figure A-1 ATD Accuracy Definitions

NOTE: *Figure A-1* shows only definitions, for specification values refer to **Table A-10**.

3. Maximum Erase and Programming times are achieved under particular combinations of f_{NVMOP} and bus frequency f_{bus} . Refer to formulae in Sections **A.3.1.1 - A.3.1.4** for guidance.
4. First Programming operations are not applicable to EEPROM
5. Minimum Erase times are achieved under maximum NVM operating frequency f_{NVMOP} .
6. Minimum time, if first word in the array is not blank
7. Maximum time to complete check on an erased block

A.3.2 NVM Reliability

The reliability of the NVM blocks is guaranteed by stress test during qualification, constant process monitors and burn-in to screen early life failures.

The failure rates for data retention and program/erase cycling are specified at the operating conditions noted.

The program/erase cycle count on the sector is incremented every time a sector or mass erase event is executed.

NOTE: All values shown in **Table A-12** are target values and subject to further extensive characterization.

Table A-12 NVM Reliability Characteristics

Conditions are shown in Table A-4 unless otherwise noted						
Num	C	Rating	Cycles	Data Retention Lifetime	Unit	
1	C	Flash/EEPROM (-40C to + 125C)	10	15	Years	
2	C	EEPROM (-40C to + 125C)	10,000	5	Years	

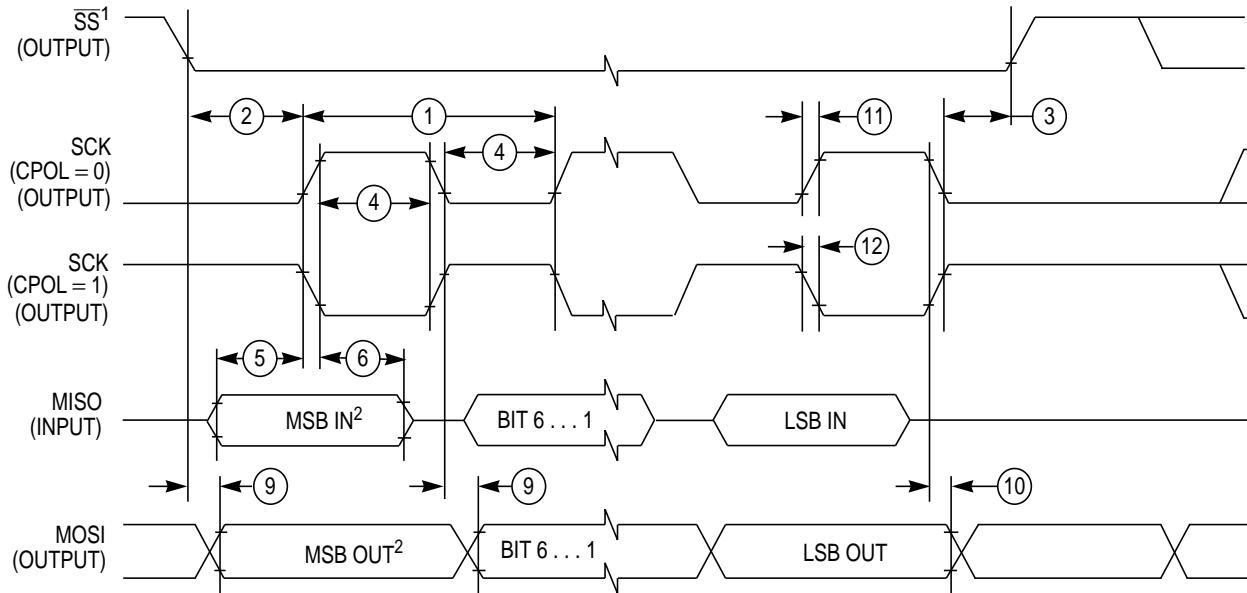
NOTE: Flash cycling performance is 10 cycles at -40C to + 125C. Data retention is specified for 15 years.

NOTE: EEPROM cycling performance is 10K cycles at -40C to +125C. Data retention is specified for 5 years on words after cycling 10K times. However if only 10 cycles are executed on a word the data retention is specified for 15 years.

A.7 SPI

A.7.1 Master Mode

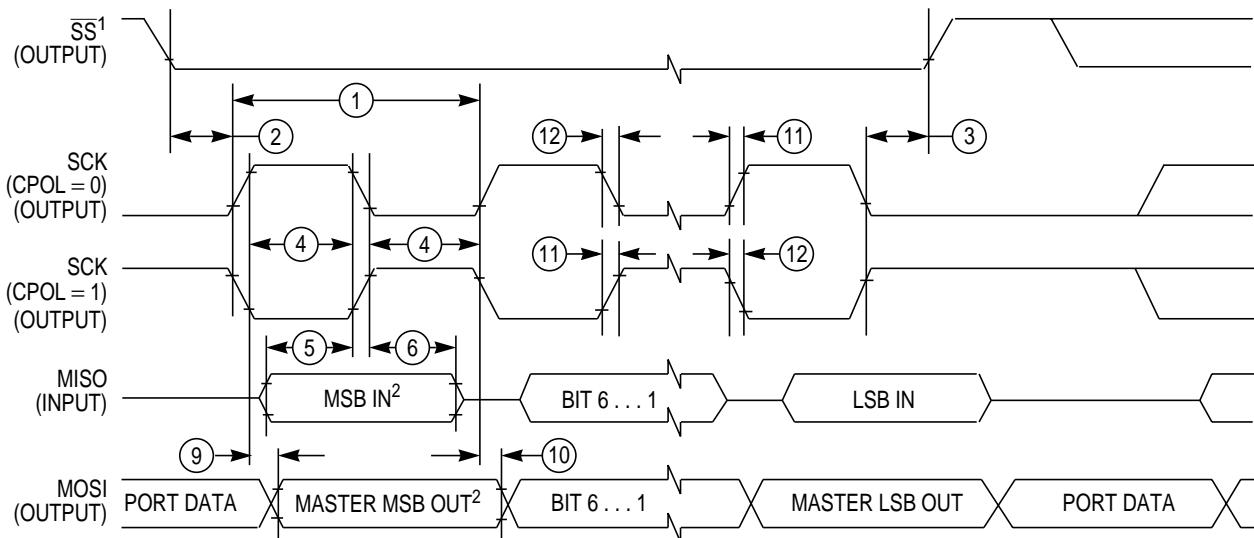
Figure A-5 and **Figure A-6** illustrate the master mode timing. Timing values are shown in **Table A-18**.



1. If configured as output.

2. LSBF = 0. For LSBF = 1, bit order is LSB, bit 1, ..., bit 6, MSB.

Figure A-5 SPI Master Timing (CPHA = 0)



1. If configured as output

2. LSBF = 0. For LSBF = 1, bit order is LSB, bit 1, ..., bit 6, MSB.

Figure A-6 SPI Master Timing (CPHA =1)

Table A-18 SPI Master Mode Timing Characteristics¹

Conditions are shown in Table A-4 unless otherwise noted, $C_{LOAD} = 200\text{pF}$ on all outputs							
Num	C	Rating	Symbol	Min	Typ	Max	Unit
1	P	Operating Frequency	f_{op}	DC		1/4	f_{bus}
1	P	SCK Period $t_{sck} = 1/f_{op}$	t_{sck}	4		2048	t_{bus}
2	D	Enable Lead Time	t_{lead}	1/2		—	t_{sck}
3	D	Enable Lag Time	t_{lag}	1/2			t_{sck}
4	D	Clock (SCK) High or Low Time	t_{wsck}	$t_{bus} - 30$		1024 t_{bus}	ns
5	D	Data Setup Time (Inputs)	t_{su}	25			ns
6	D	Data Hold Time (Inputs)	t_{hi}	0			ns
9	D	Data Valid (after Enable Edge)	t_v			25	ns
10	D	Data Hold Time (Outputs)	t_{ho}	0			ns
11	D	Rise Time Inputs and Outputs	t_r			25	ns
12	D	Fall Time Inputs and Outputs	t_f			25	ns

NOTES:

1. The numbers 7, 8 in the column labeled "Num" are missing. This has been done on purpose to be consistent between the Master and the Slave timing shown in **Table A-19**.

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